ABSTRACT

Methods of testing circuits for degradation of electrical signals and compensating for this degradation are disclosed. One such method involves visually comparing a visual representation of a reference signal generated by a test signal source, which can be made substantially identical to an original signal, and a degraded signal generated by another test signal source after passing through a video system. The degraded image is then adjusted to visually match the reference image. Another disclosed method involves converting a degraded signal that has passed through a video system into two substantially identical copies of said degraded video signal and then adjusting one of the two substantially identical copies of said degraded video signal to compensate for the degradation of the system while comparing it with the other substantially identical copy of said degraded signal which remains uncompensated.

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